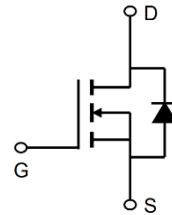


250V N-Channel Enhancement Mode MOSFET
Description

The AP90N25MP is silicon N-channel Enhanced VDMOSFETs, is obtained by the self-aligned planar Technology which reduce the conduction loss, improve switching performance and enhance the avalanche energy. The transistor can be used in various power switching circuit for system miniaturization and higher efficiency.


General Features

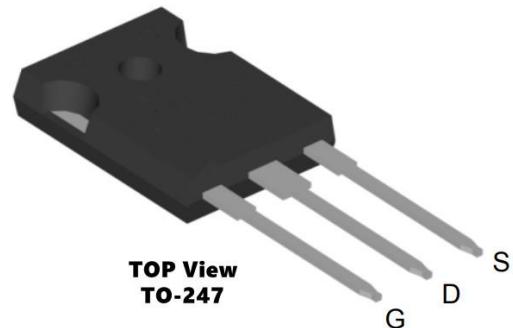
$V_{DS} = 200V$ $I_D = 90A$

$R_{DS(ON)} < 35m\Omega$ @ $V_{GS}=10V$ (**Type: 30m Ω**)

Application

Uninterruptible Power Supply(UPS)

Power Factor Correction (PFC)


Package Marking and Ordering Information

| Product ID | Pack | Marking | Qty(PCS) |
|------------|-----------|--------------------|----------|
| AP90N25MP | TO-247-3L | AP90N25MP XXX YYYY | 300 |

Absolute Maximum Ratings ($T_c=25^\circ C$ unless otherwise noted)

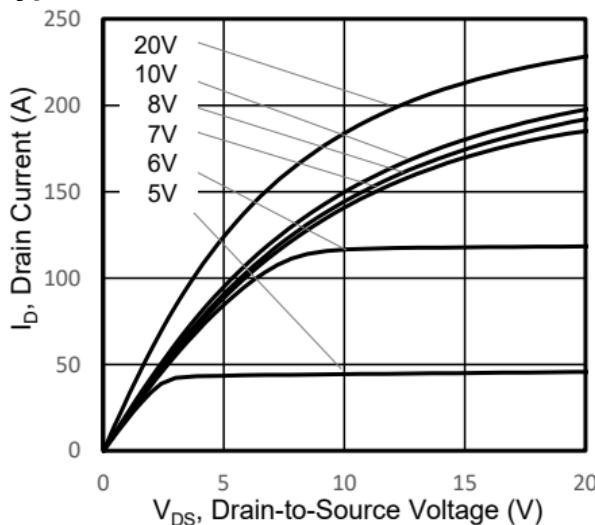
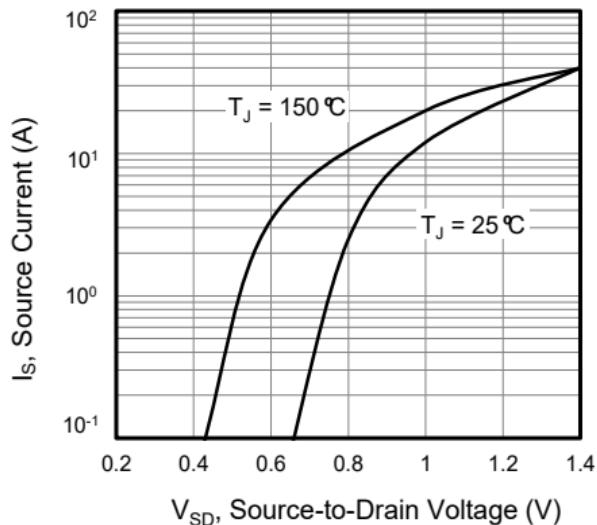
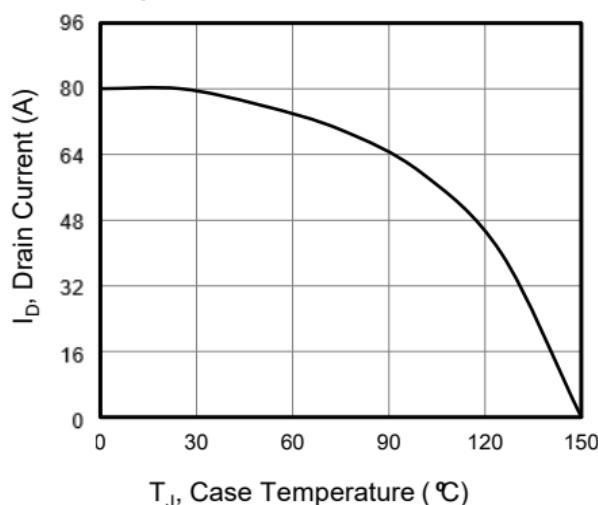
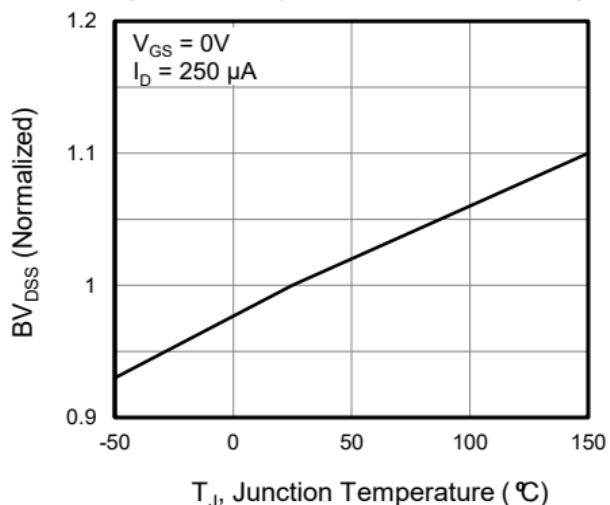
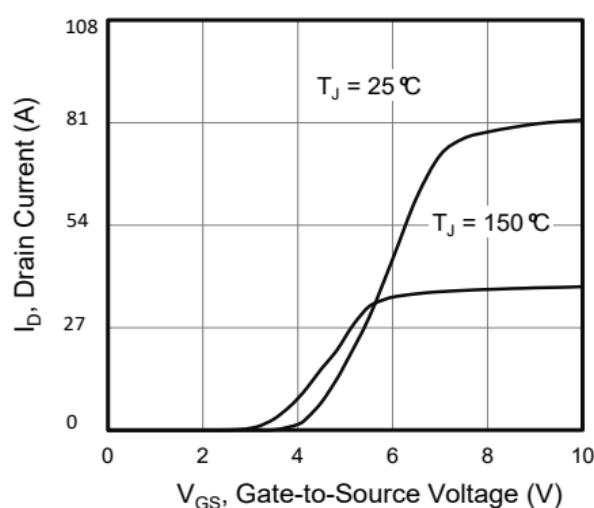
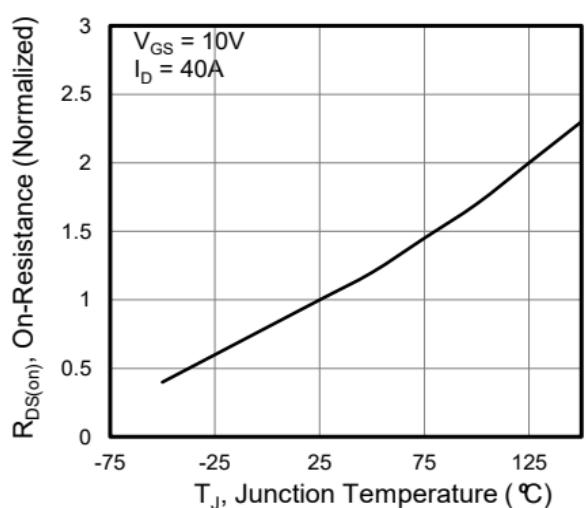
| Symbol | Parameter | Value | Unit |
|----------------|--|----------|------|
| $VDSS$ | Drain-Source Voltage ($V_{GS} = 0V$) | 250 | V |
| ID | Continuous Drain Current | 90 | A |
| IDM | Pulsed Drain Current | 360 | A |
| $VGSS$ | Gate-Source Voltage | ± 20 | V |
| EAS | Single Pulse Avalanche Energy | 2000 | mJ |
| IAS | Avalanche Current | 20 | A |
| EAR | Repetitive Avalanche Energy | 8 | mJ |
| P_D | Power Dissipation ($T_c = 25^\circ C$) | 140 | W |
| T_J, T_{stg} | Operating Junction and Storage Temperature Range | -55~+150 | °C |
| R_{thJC} | Thermal Resistance, Junction-to-Case | 0.89 | °C/W |
| R_{thJA} | Thermal Resistance, Junction-to-Ambient | 40 | °C/W |

250V N-Channel Enhancement Mode MOSFET
Electrical Characteristics ($T_J=25^\circ\text{C}$, unless otherwise noted)

| Parameter | Symbol | Test Conditions | Min. | Typ. | Max. | Units |
|----------------|-----------------------------------|---|------|------|-----------|------------------|
| V(BR)DSS | Drain-SourceBreakdown Voltage | $V_{GS} = 0\text{V}$, $I_D = 250\mu\text{A}$ | 250 | 285 | -- | V |
| IDSS | Zero Gate Voltage Drain Current | $V_{DS} = 250\text{V}$, $V_{GS} = 0\text{V}$, $T_J = 25^\circ\text{C}$ | -- | -- | 1 | μA |
| IGSS | Gate-Source Leakage | $V_{GS} = \pm 30\text{V}$ | -- | -- | ± 100 | nA |
| VGS(th) | Gate-Source Threshold Voltage | $V_{DS}=V_{GS}$, $I_D = 250\mu\text{A}$ | 2.0 | 3.0 | 4.0 | V |
| RDS(on) | Drain-SourceOn-Resistance (Note3) | $V_{GS}=10\text{V}$, $I_D = 40\text{A}$ | -- | 30 | 35 | $\text{m}\Omega$ |
| Ciss | Input Capacitance | $V_{GS} = 0\text{V}$, $V_{DS} = 25\text{V}$, $f = .0\text{MHz}$ | -- | 5784 | -- | pF |
| Coss | Output Capacitance | | -- | 893 | -- | |
| Crss | Reverse Transfer Capacitance | | -- | 561 | -- | |
| Qg | Total Gate Charge | $V_{DD} = 200\text{V}$, $I_D = 80\text{A}$, $V_{GS} = 10\text{V}$ | -- | 376 | -- | nC |
| Qgs | Gate-Source Charge | | -- | 33.8 | -- | |
| Qgd | Gate-Drain Charge | | -- | 177 | -- | |
| td(on) | Turn-on Delay Time | $V_{DD} = 125\text{V}$, $I_D = 80\text{A}$, $R_G = 25\Omega$ | -- | 55 | -- | ns |
| t _r | Turn-on Rise Time | | -- | 165 | -- | |
| td(off) | Turn-off Delay Time | | -- | 1050 | -- | |
| t _f | Turn-off Fall Time | | -- | 367 | -- | |
| IS | Continuous Body Diode Current | $T_C = 25^\circ\text{C}$ | -- | -- | 90 | A |
| ISM | Pulsed Diode Forward Current | | -- | -- | 320 | A |
| VSD | Body Diode Voltage | $T_J = 25^\circ\text{C}$, $I_{SD} = 22.5\text{A}$, $V_{GS} = 0\text{V}$ | -- | -- | 1.4 | V |
| trr | Reverse Recovery Time | $V_{DD}=125\text{V}$ $V_{GS} = 0\text{V}$, $I_S = 30\text{A}$, $dI_F/dt = 100\text{A}/\mu\text{s}$ | -- | 360 | -- | ns |
| Qrr | Reverse Recovery Charge | | -- | 5.61 | -- | μC |

Note :

- 1、The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2、The EAS data shows Max. rating . IAS = 20A, VDD = 50V, RG = 25 Ω , Starting TJ = 25 $^\circ\text{C}$
- 3、The test condition is Pulse Test: Pulse width $\leq 300\mu\text{s}$, Duty Cycle $\leq 1\%$
- 4、The power dissipation is limited by 150 $^\circ\text{C}$ junction temperature
- 5、The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation.

Typical Characteristics

Figure 1. Output Characteristics

Figure 2. Body Diode Forward Voltage

Figure 3. Drain Current vs. Temperature

Figure 4. BVDSS Variation vs. Temperature

Figure 5. Transfer Characteristics

Figure 6. On-Resistance vs. Temperature


250V N-Channel Enhancement Mode MOSFET

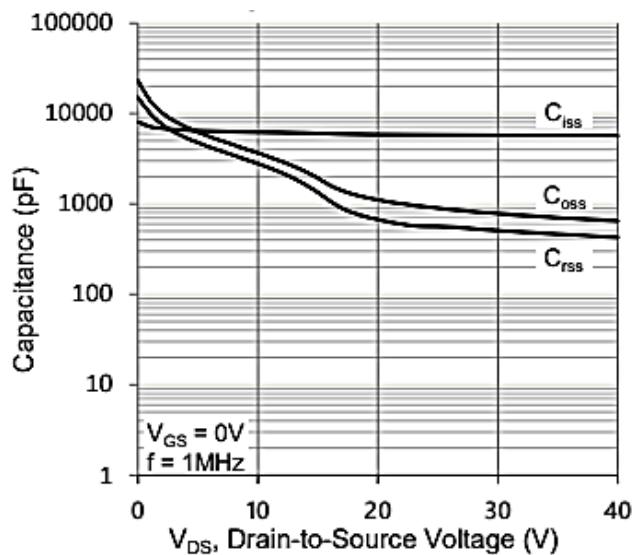


Figure 7. Capacitance

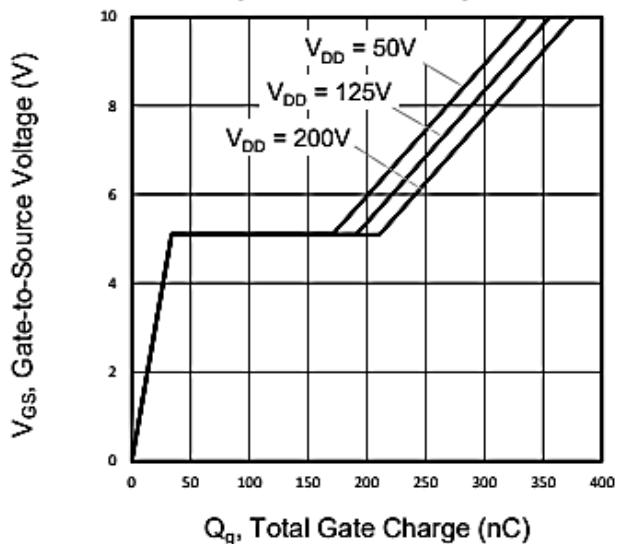


Figure 8. Gate Charge

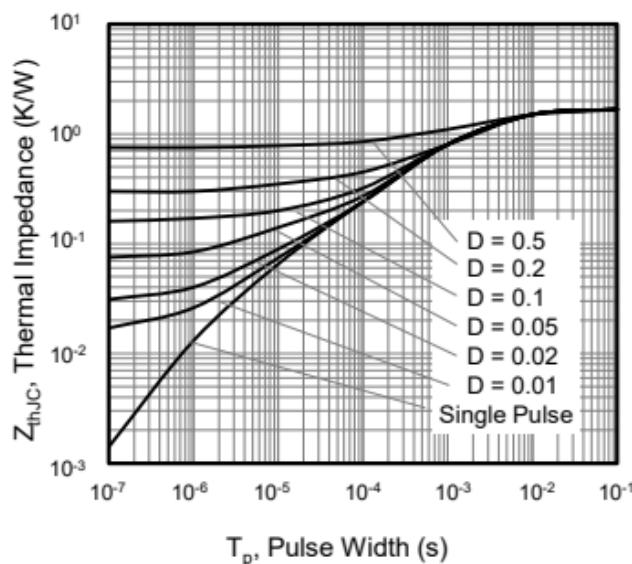
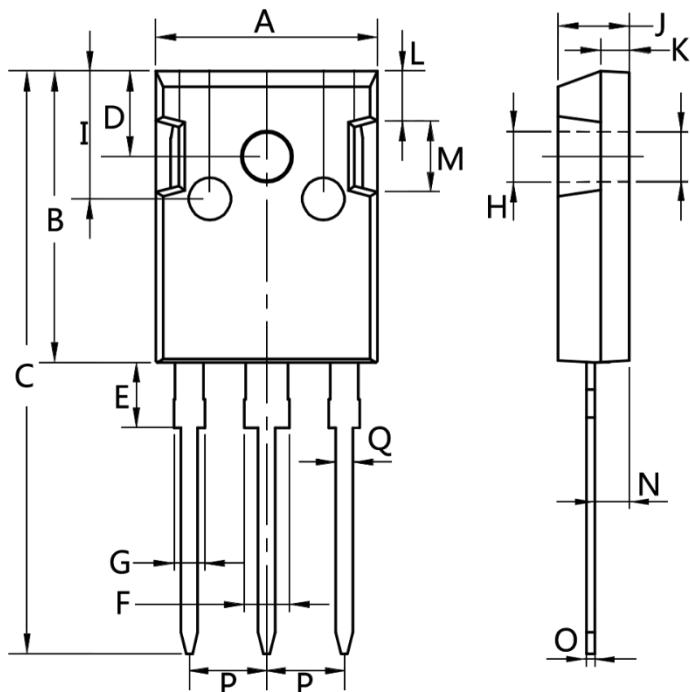


Figure 9. Transient Thermal Impedance

250V N-Channel Enhancement Mode MOSFET
Package Mechanical Data-TO-247-3L


| Dim. | Min. | Max. |
|------|----------|------|
| A | 15.0 | 16.0 |
| B | 20.0 | 21.0 |
| C | 41.0 | 42.0 |
| D | 5.0 | 6.0 |
| E | 4.0 | 5.0 |
| F | 2.5 | 3.5 |
| G | 1.75 | 2.5 |
| H | 3.0 | 3.5 |
| I | 8.0 | 10.0 |
| J | 4.9 | 5.1 |
| K | 1.9 | 2.1 |
| L | 3.5 | 4.0 |
| M | 4.75 | 5.25 |
| N | 2.0 | 3.0 |
| O | 0.55 | 0.75 |
| P | Typ 5.08 | |
| Q | 1.2 | 1.3 |